



1200V, 50A, 50mΩ

# Silicon Carbide Power MOSFET

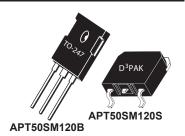
## **FEATURES**

- · Fast switching with low EMI/RFI
- Low Switching Energy
- Low R<sub>DS(on)</sub> Temperature Coefficient For Improved Efficiency
- · Low gate charge
- · Short Circuit Withstand Rated
- RoHS compliant

# A

## **TYPICAL APPLICATIONS**

- PFC and other boost converter
- Buck converter
- Two switch forward (asymmetrical bridge)
- · Single switch forward
- Flyback
- · Inverters





## **Maximum Ratings**

Symbol	Parameter	Ratings	Unit
	Continuous Drain Current @ T <sub>c</sub> = 25°C	47	
I <sub>D</sub>	Continuous Drain Current @ T <sub>c</sub> = 100°C	40	Α
I <sub>DM</sub>	Pulsed Drain Current <sup>①</sup>	100	
V <sub>GS</sub>	Gate-Source Voltage	-10 to +25	V
SCWT	Short Circuit Withstand Time: $V_{DD}$ = 960V, $V_{GS}$ = 20V, $T_{C}$ =25°C	4.5	μs
-	Total Power Dissipation @ T <sub>c</sub> = 25°C	273	W
$P_{D}$	Linear Derating Factor	1.82	W/°C

#### **Thermal and Mechanical Characteristics**

Symbol	Characteristic	Min	Тур	Max	Unit	
R <sub>øJC</sub>	Junction to Case Thermal Resistance			0.55	°C/W	
$T_{J}, T_{STG}$	Operating and Storage Junction Temperature Range	-55		175	°C	
T <sub>L</sub>	Soldering Temperature for 10 Seconds (1.6mm from case)			260		
Torque	Mounting Torque (TO-247 Package), 6-32 or M3 screw			10	in∙lbf	
				1.1	N·m	

#### **Static Characteristics**

# T<sub>J</sub> = 25°C unless otherwise specified

Symbol	Parameter	Test Conditions		Min	Тур	Max	Unit
V <sub>BR(DSS)</sub>	Drain-Source Breakdown Voltage	$V_{GS} = 0V, I_D = 1mA$		1200			V
$\Delta V_{BR(DSS)} / \Delta T_{J}$	Breakdown Voltage Temperature Coefficient	Reference to 25°C, I <sub>D</sub> = 1mA			0.250		V/°C
R <sub>DS(on)</sub>	Drain-Source On Resistance©	V <sub>GS</sub> = 20V, I <sub>D</sub> = 20A			50	65	mΩ
V <sub>GS(th)</sub>	Gate-Source Threshold Voltage	$V_{GS} = V_{DS}$ , $I_D = 1 \text{mA}$		1.7	2.4		V
$\Delta V_{GS(th)}/\Delta T_{J}$	Threshold Voltage Temperature Coefficient				-6.4		mV/°C
	Zero Gate Voltage Drain Current	$V_{DS} = 1200V$ $T_{J} = 25^{\circ}C$ $T_{J} = 125^{\circ}C$	T <sub>J</sub> = 25°C		10	100	
DSS	Zero Gate voltage Drain Current				500	μΑ	
I <sub>GSS</sub>	Gate-Source Leakage Current	V <sub>GS</sub> = +20V / -10V				±100	nA
ESR	Equivalent Series Resistance	f = 1MHz, 25mV, Drain Short			1.27		Ω

## **Dynamic Characteristics**

# T<sub>J</sub> = 25°C unless otherwise specified

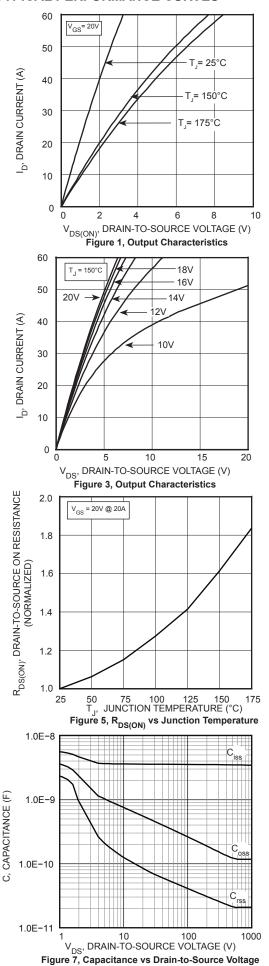
Symbol	Parameter	Test Conditions	Min	Тур	Max	Unit
C <sub>iss</sub>	Input Capacitance	V = 0V V = 4000V		3460		
C <sub>rss</sub>	Reverse Transfer Capacitance	$V_{GS} = 0V, V_{DD} = 1000V$ f = 1MHz		21		pF
C <sub>oss</sub>	Output Capacitance	T = TIVITZ		117		
$Q_g$	Total Gate Charge	V <sub>GS</sub> = 0/20V		166		nC
$Q_{gs}$	Gate-Source Charge	V <sub>DD</sub> = 800V		66		
$Q_{gd}$	Gate-Drain Charge	I <sub>D</sub> = 20A		29		
t <sub>d(on)</sub>	Turn-On Delay Time	V <sub>DD</sub> = 800V		11		ns
t,	Current Rise Time	$V_{GS} = 20V$		9		
t <sub>d(off)</sub>	Turn-Off Delay Time	I <sub>D</sub> = 20A		55		
t <sub>r</sub>	Current Fall Time	$R_{_{\rm G}}$ = 0.7 $\Omega$ ③		29		
E <sub>on2</sub>	Turn-On Switching Energy <sup>(4)</sup>	L = 115 μH		408		1
E <sub>off</sub>	Turn-Off Switching Energy	T <sub>c</sub> = 25°C		143		μJ
t <sub>d(on)</sub>	Turn-On Delay Time	V <sub>DD</sub> = 800V		8		
t,	Current Rise Time	$V_{GS} = 20V$ $I_{D} = 20A$ $R_{G} = 0.7 \Omega$ $^{\textcircled{3}}$		8		no
t <sub>d(off)</sub>	Turn-Off Delay Time			64		ns
t <sub>r</sub>	Current Fall Time			32		
E <sub>on2</sub>	Turn-On Switching Energy <sup>®</sup>	L = 115 μH T <sub>c</sub> = 150°C		386		1
E <sub>off</sub>	Turn-Off Switching Energy			164		μJ

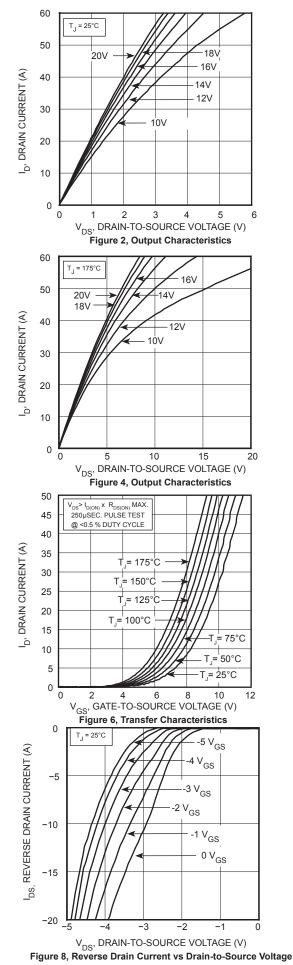
### **Source-Drain Diode Characteristics**

# T<sub>J</sub> = 25°C unless otherwise specified

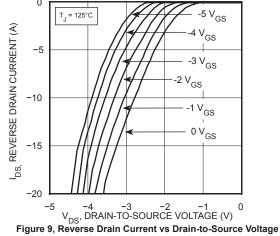
Symbol	Parameter	Test Conditions	Min	Тур	Max	Unit
V <sub>SD</sub>	Diode Forward Voltage	I <sub>SD</sub> = 20A, T <sub>J</sub> = 25°C, V <sub>GS</sub> = 0V		3.91		V
t <sub>rr</sub>	Reverse Recovery Time	$I_{SD} = 20A, V_{DD} = 800V$ $dI/dt = 100A/\mu s, T_{J} = 25^{\circ}C$		120		ns
Q <sub>rr</sub>	Reverse Recovery Charge			90		nC
I <sub>rrm</sub>	Reverse Recovery Current			1.9		Α

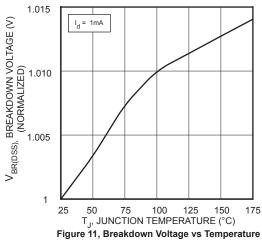
- (1) Repetitive Rating: Pulse width and case temperature limited by maximum junction temperature.
- ② Pulse test: Pulse Width <  $380\mu s$ , duty cycle < 2%.
- 3 R<sub> $_{G}$ </sub> is total gate resistance including internal gate driver impedance (MIC4452).
- 4 Free wheeling diode APT10SCD120B.





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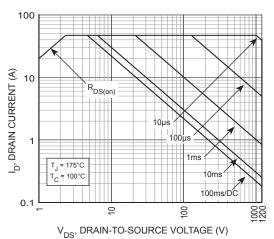
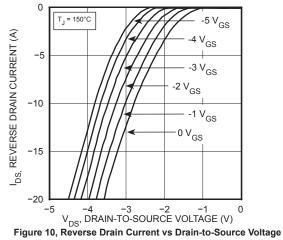


Figure 13, Forward Safe Operating Area



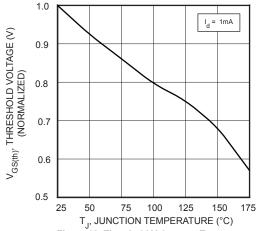
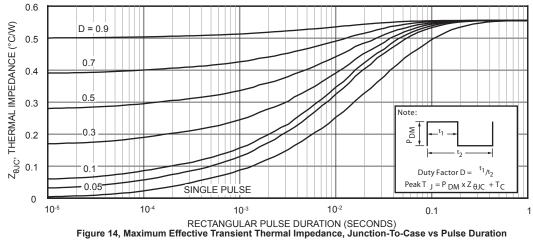
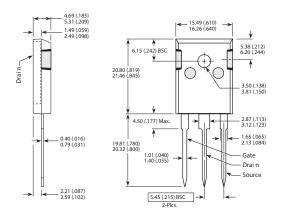


Figure 12, Threshold Voltage vs Temperature

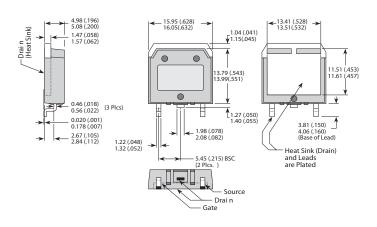


#### TO-247 (B) Package Outline

@1 SAC: Tin, Silver, Copper



## D³PAK (S) Package Outline



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